

<b>Notice of References Cited</b>	Application/Control No. 10/574,678		Applicant(s)/Patent Under Reexamination EDEL BROCK, RALF	
	Examiner ANNIE MOY		Art Unit 4147	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,016,049 A	05-1991	Onishi et al.	399/32
*	B	US-6,097,444 A	08-2000	Nakano, Takao	348/607
*	C	US-2003/0016297 A1	01-2003	Shigeta, Kazuyuki	348/304
*	D	US-6,633,286 B1	10-2003	Do et al.	345/205
*	E	US-2005/0134557 A1	06-2005	Feng et al.	345/156
*	F	US-2005/0156867 A1	07-2005	Edelbrock, Ralf	345/102
*	G	US-2005/0283344 A1	12-2005	Moscovitch, Jerry	702/189
*	H	US-2007/0085816 A1	04-2007	Evanicky et al.	345/102
*	I	US-2007/0273290 A1	11-2007	Ashdown et al.	315/113
*	J	US-2007/0279384 A1	12-2007	Brosnan, Michael J.	345/166
*	K	US-2008/0094081 A1	04-2008	Nguyen et al.	324/750
*	L	US-2008/0123908 A1	05-2008	Waldman et al.	382/124
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

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